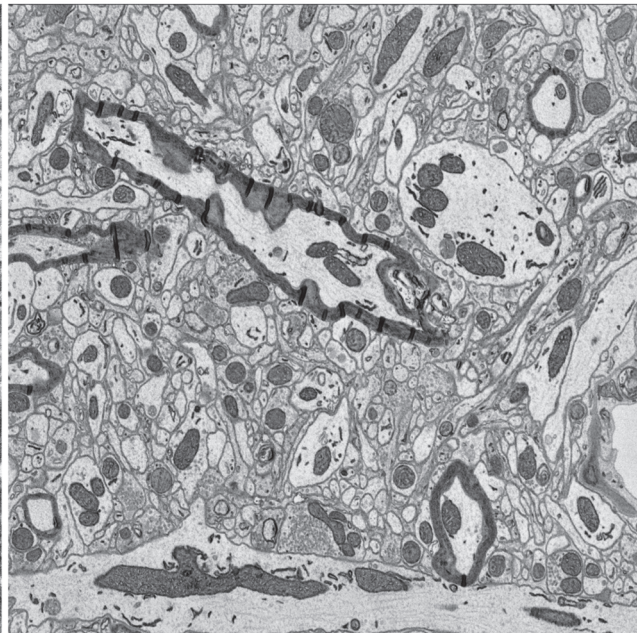
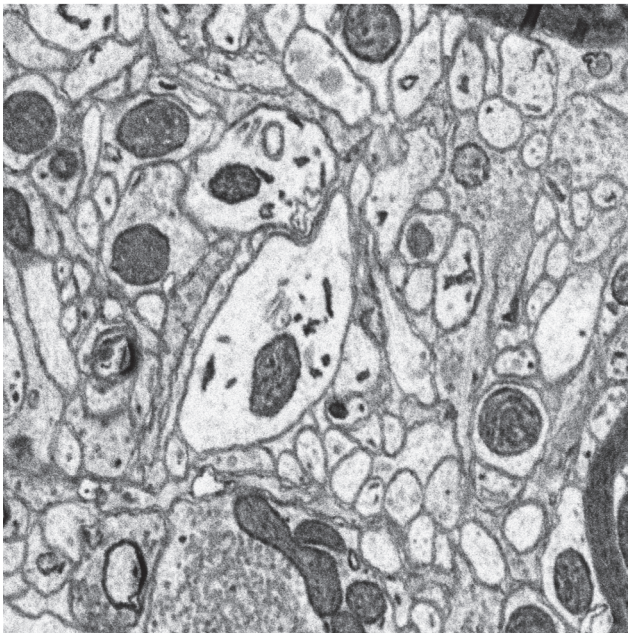
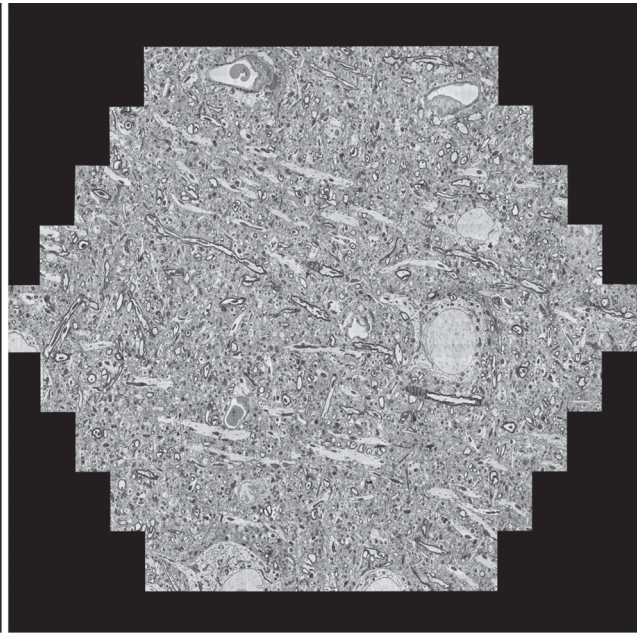
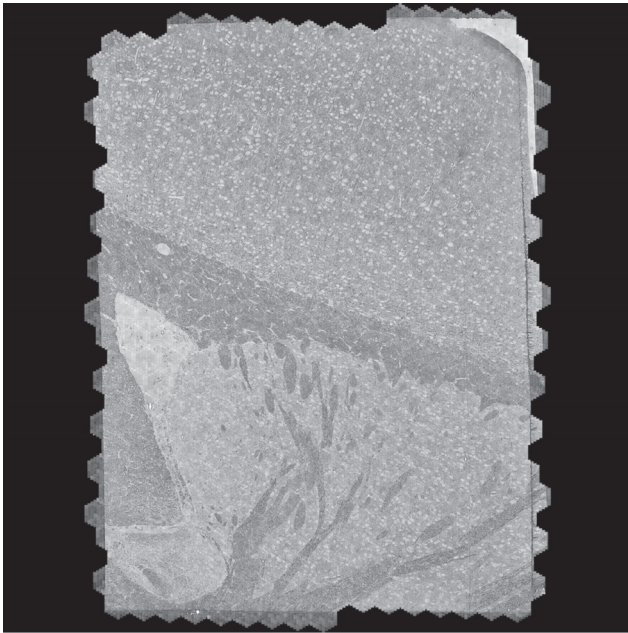


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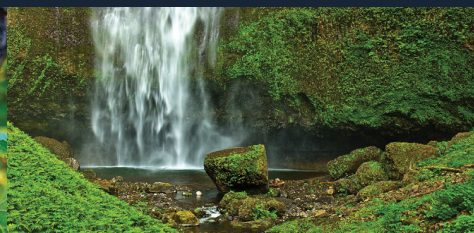
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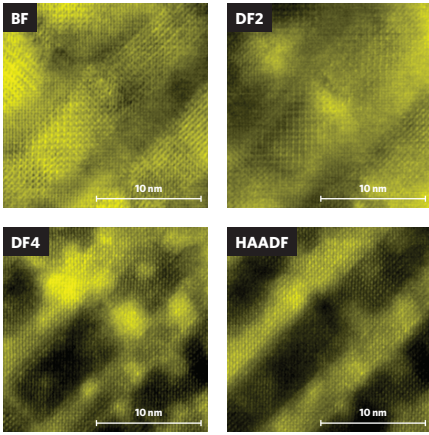


<http://microscopy.org/MandM/2015>

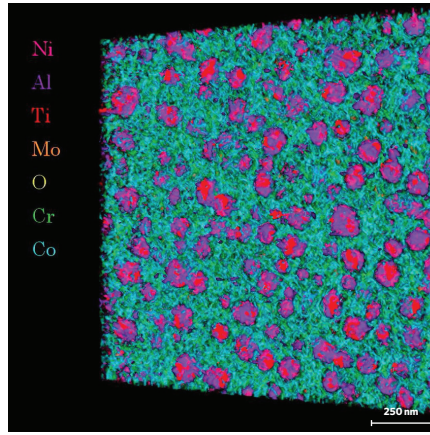


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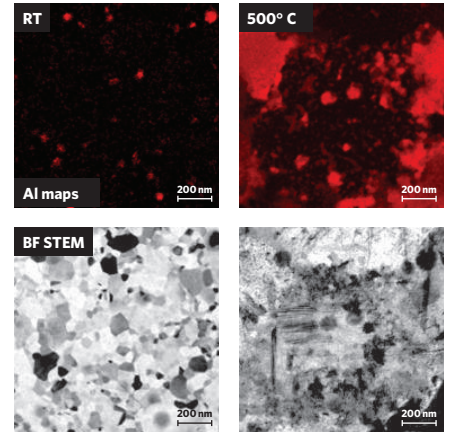




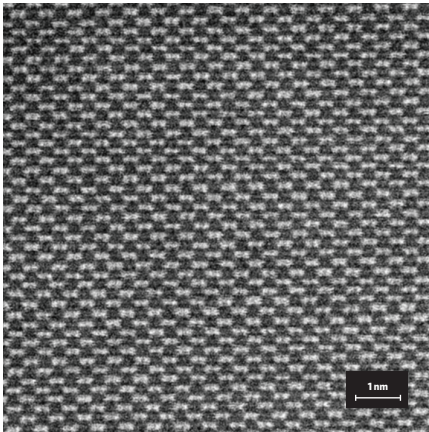
4 channel simultaneous HRSTEM imaging of SrTiO₃ using 4 STEM detectors.



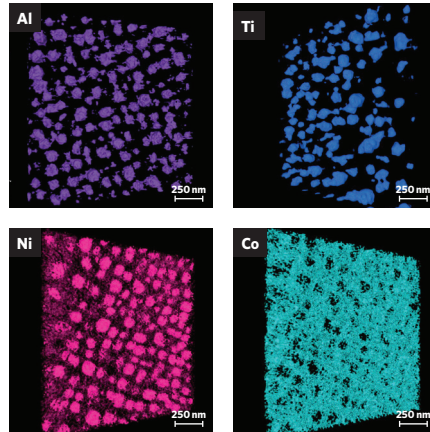
Combined 3D EDS map: Ni, Al, Ti, Mo, Cr, and Co.



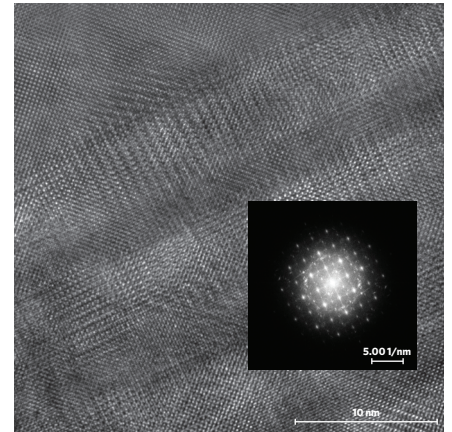
Temperature driven Al aggregation in solar cell. Sample courtesy of Dr. S. Kraschewski, U. Erlangen.



HRSTEM of Si (110) at 200kV.



3D EDS maps at different angles.



HRTEM image of SrTiO₃ with Ceta 16M camera.

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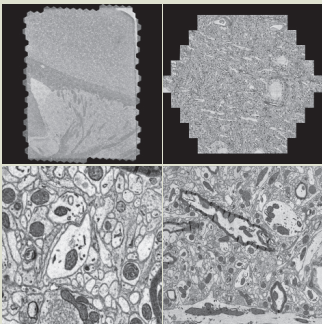


Image of mouse brain tissue acquired by the first commercial multi-beam SEM. Increasing magnification clockwise from upper left. Upper left is a montage of 28,000 single-beam images (image width = 1.54 mm). Lower left is from the same dataset (image width = 4 μm).

See article by Eberle et al.

Meeting Report

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Pavel Hozák, IMC 2014 Chairman and Czechoslovak Microscopy Society President

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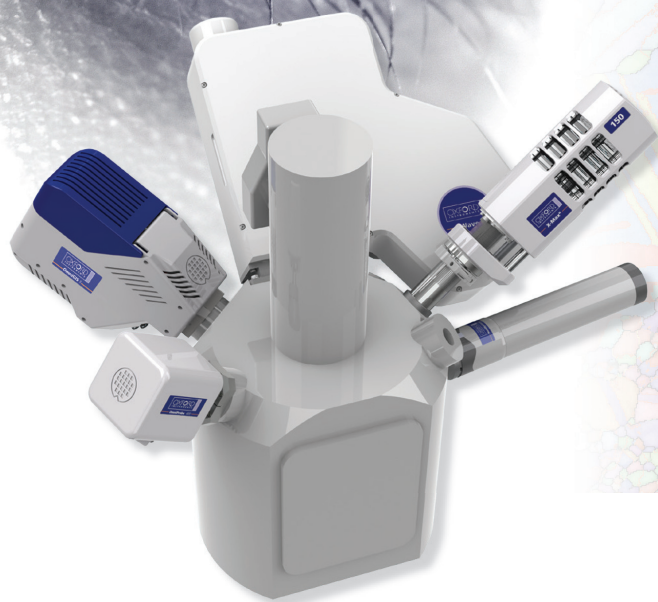
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TKD IPF map of strained Cu. Step size 4 nm. Courtesy: Saritha Samudrala, Kevin Hemker and Pat Trimby.

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